

NANONET⁺ Annual Workshop 2021

(Klingenberg, Germany)

Top-down Fabrication of Silicon Photonic Structures by Metal Assisted Chemical Etching (MACEtch)

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People Working Together

Characterization team

- M. Hollenbach
- U. Kentsch
- Dr. Y. Berencén
- PD Dr. habil. G. Astakhov



Fabrication team

- G. Schnabel
- B. Scheumann
- T. Schönherr
- C. Neisser
- J. Baratech (Summer student 2021)
- Dr. C. Fowley
- Dr. Y. Georgiev
- PD Dr. habil. A. Erbe
- Dr. W. Lee (KRISS, South Korea)



“None of us is as smart as all of us!”

Quantum Technology

Hot topics

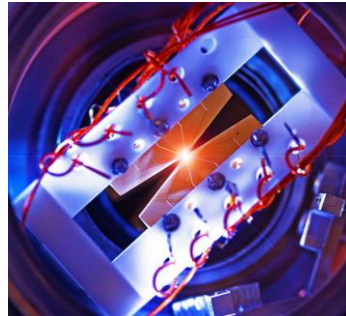


Quantum sensing

Quantum communication

Quantum computing

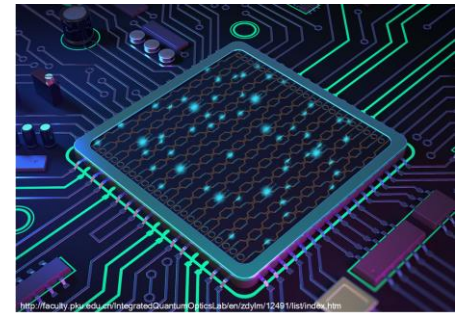
Hardware platforms



Trapped ions



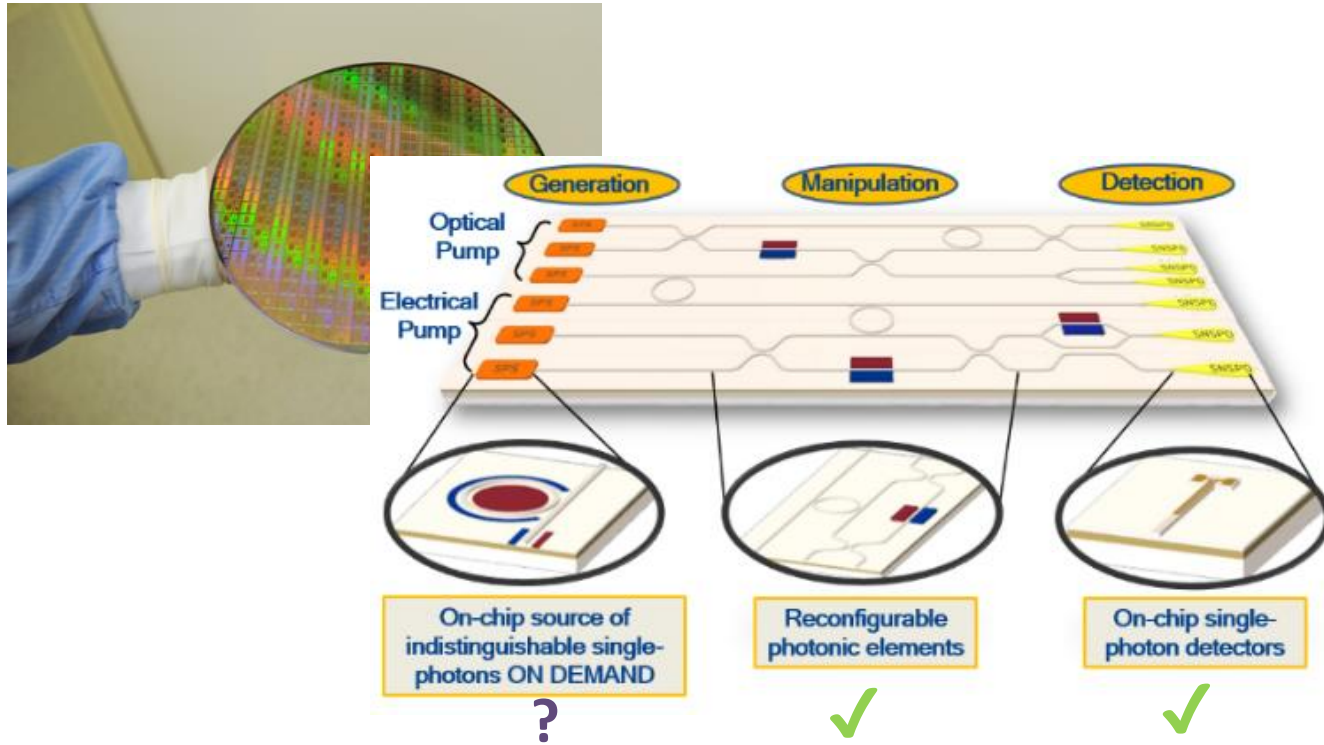
Superconducting qubits



Photonic qubits

Quantum communication using photonic qubits

Why silicon?



Quantum Photonic Integrated Circuit (QPIC)

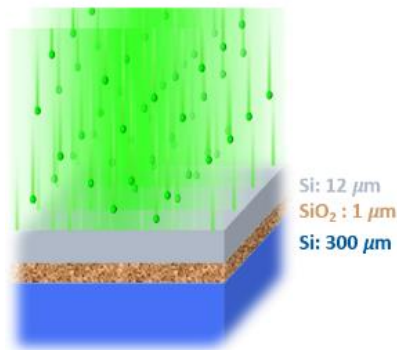
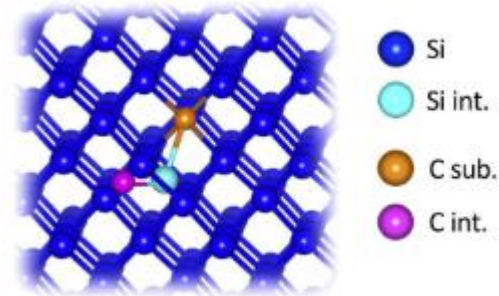
The missing link => On-chip photon source in silicon



Single-Photon Emitters in Si

G-center:

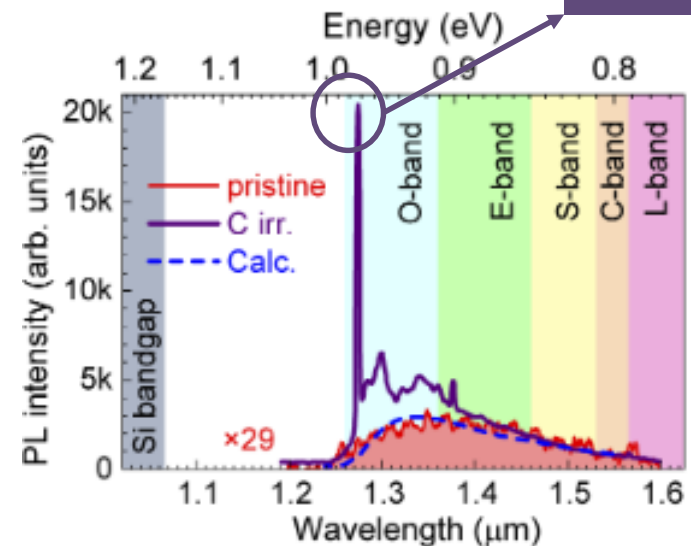
- Carbon related radiation damage
- Defect's atomic configuration



Low Temp PL



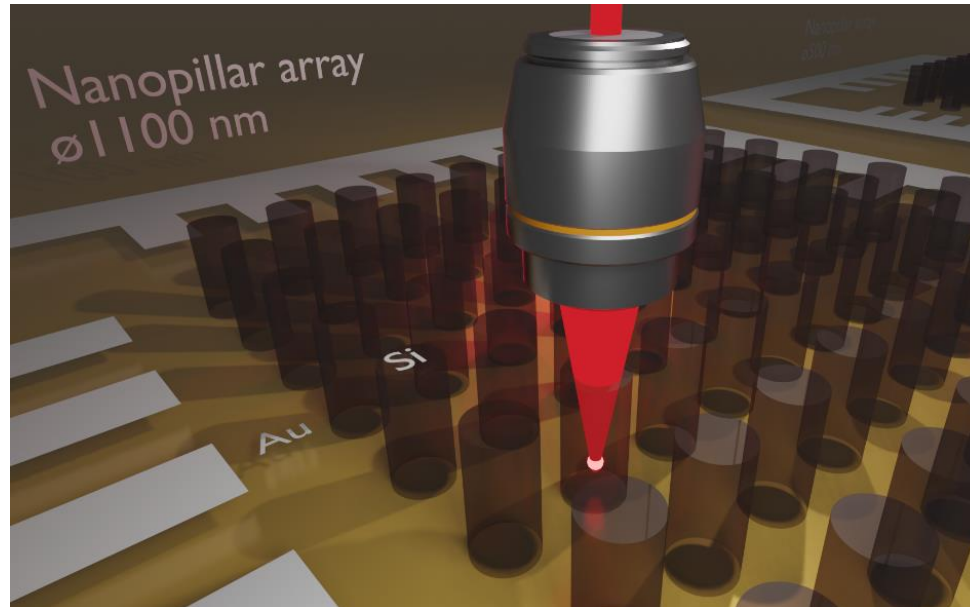
carbon implantation:
 $1 \times 10^9 \text{ cm}^{-2}$, 5.5 keV, $R_p \sim 20 \text{ nm}$



Silicon as a potential single photon source!



Integration of a single G-center in a photonic structure

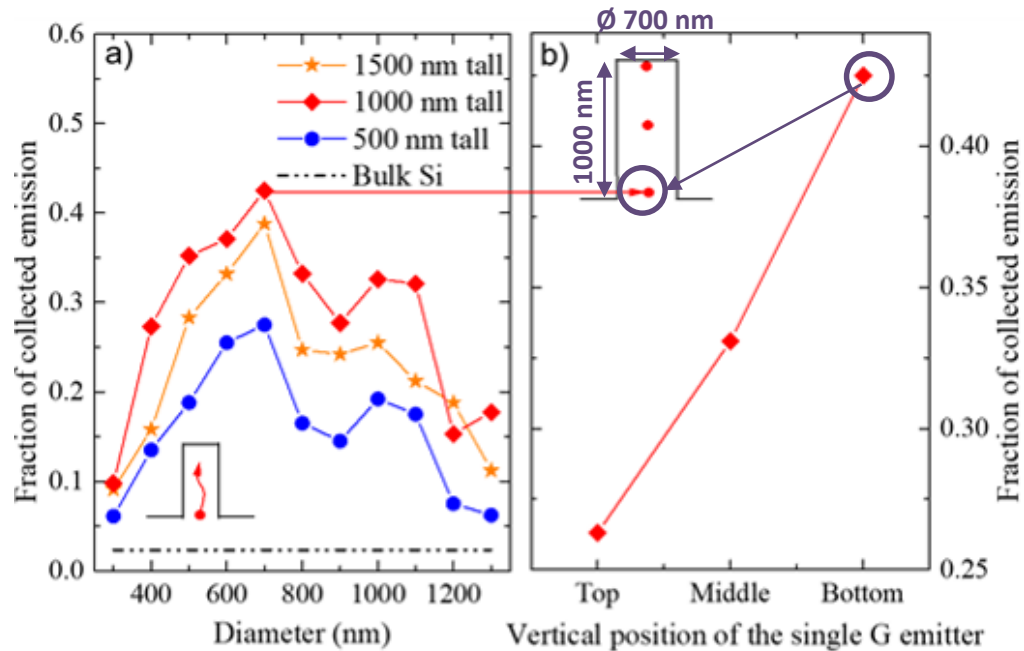


Enhancement in PL by wave guiding

Pillar as a Photonic Structure



Designing the Pillars



COMSOL simulations

G-center at the bottom of $\varnothing 700$ nm, 1000 nm tall pillar



Fabrication Method for Pillars

Requirements:

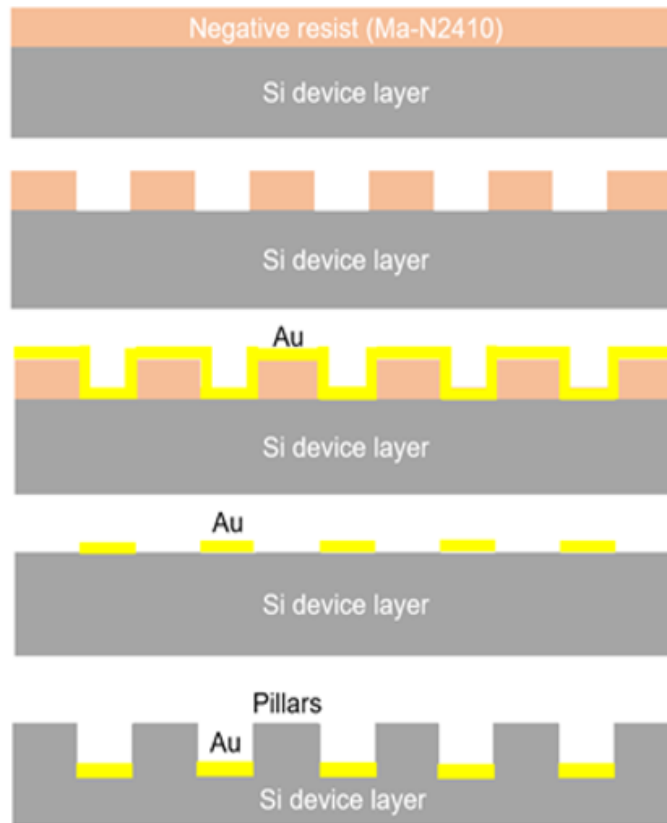
1. No lattice damage
2. Anisotropic etching
3. Smooth and uniform structures

	Wet etch	Dry etch	MACEtch
Ion induced damage	None	Mild to severe	None
Directionality	Isotropic	Anisotropic	Anisotropic
Sidewall smoothness	Smooth	Not smooth	Smooth or rough

MACEtch is more suitable.



Fabrication Steps



1. Spin coating

2. Pattern transfer by
Electron Beam Lithography

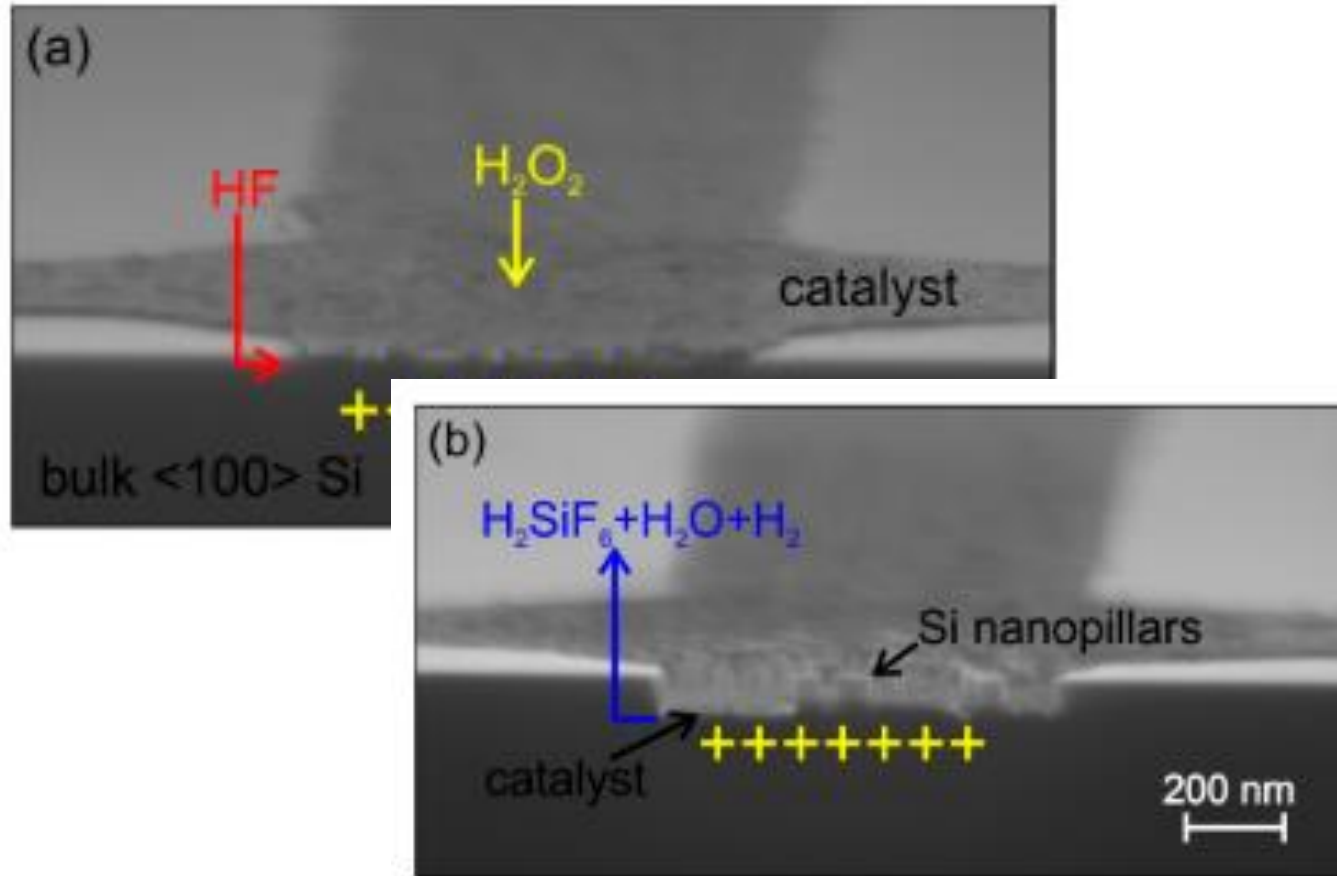
3. Metal deposition

4. Lift-off

5. MACEtch



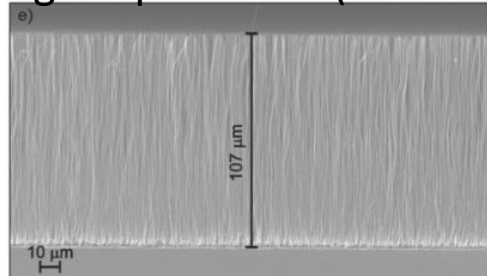
Mechanism of MACEtch





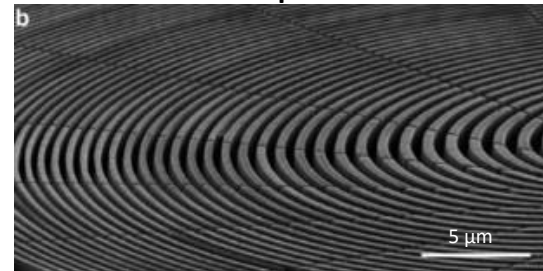
Applications of MACETech

High aspect ratio (10000:1)



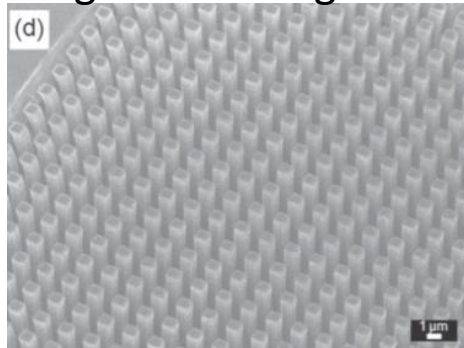
Nanoscale Horizons, 5(5), 869–879 (2020)

Zone plates



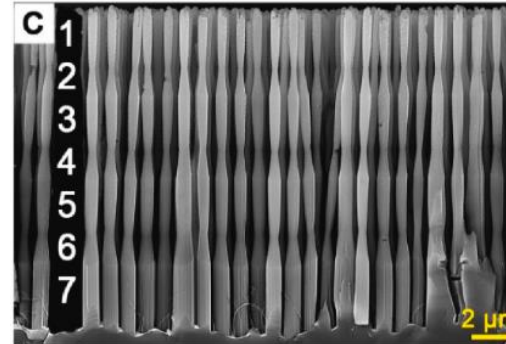
Nature Communications, 5(May), 1–7 (2014)

Magnetic force guide



Nanotechnology, 29(28) (2018)

Pillars with constrictions

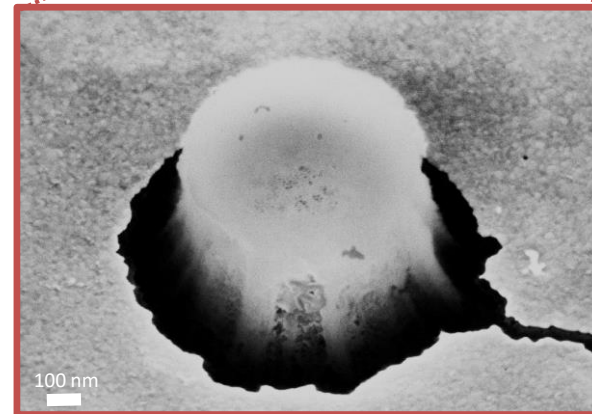
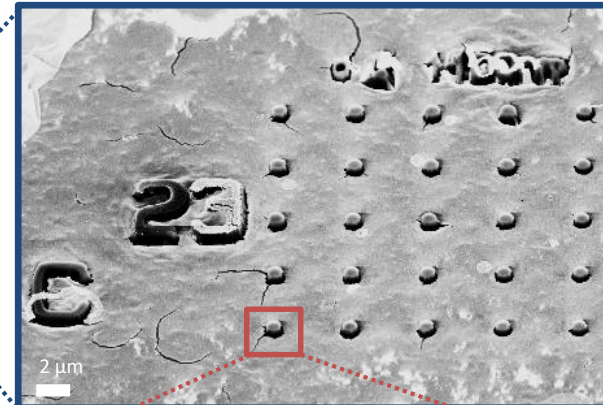
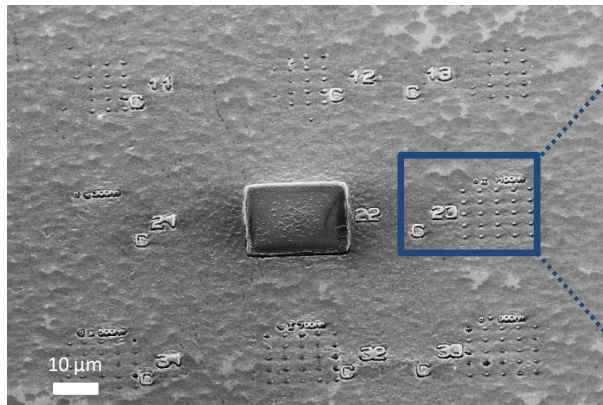


Nanotechnology, 29(28) (2021)

MACETech is versatile!



Fabricated Pillars and PL for Pristine sample

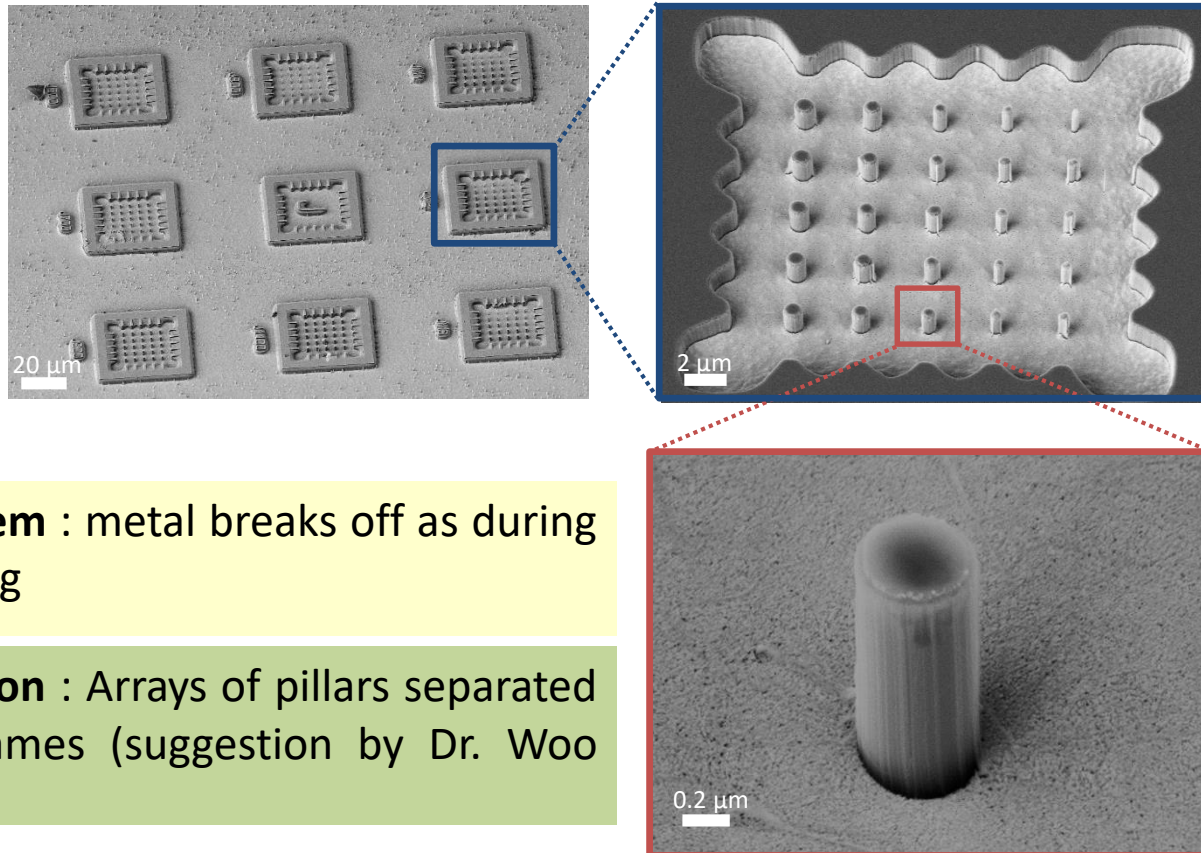


- Non uniform structures
- Gold breaks off
- Rough sidewalls
- PL shows no G-centers

MACEtch optimization
Defect-free structures



MACEtch Optimization



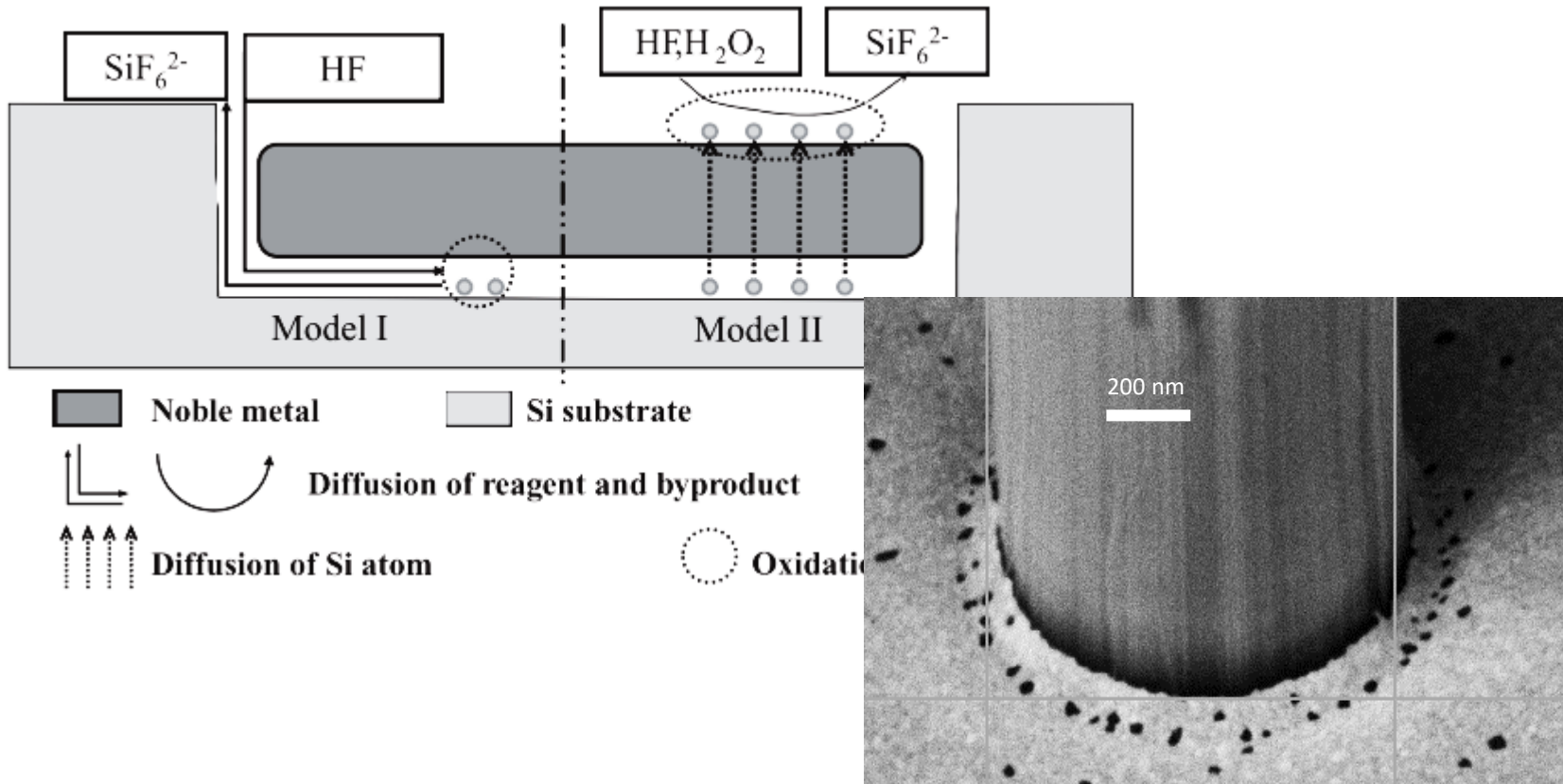
Problem : metal breaks off as during etching

Solution : Arrays of pillars separated by frames (suggestion by Dr. Woo Lee)

Smooth and uniform pillars!



Understanding MACEtch

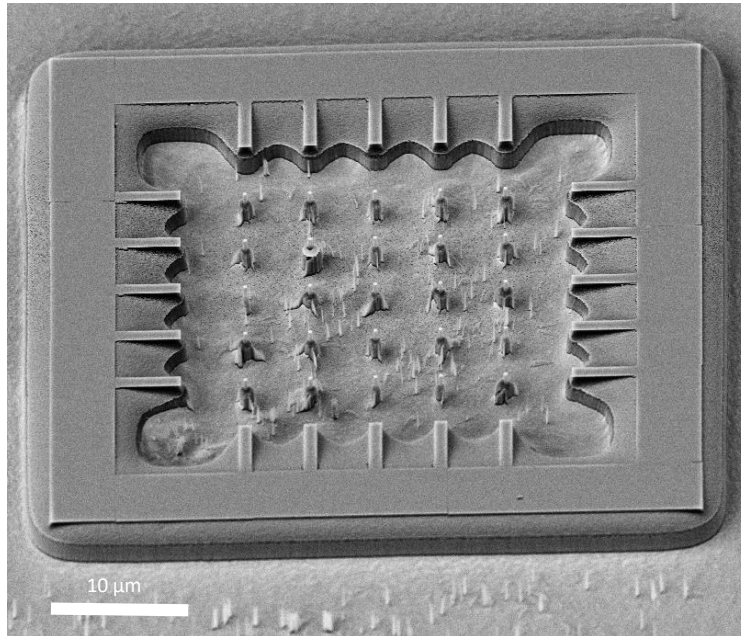


Ratio of circumference to the pitch of the structures critical

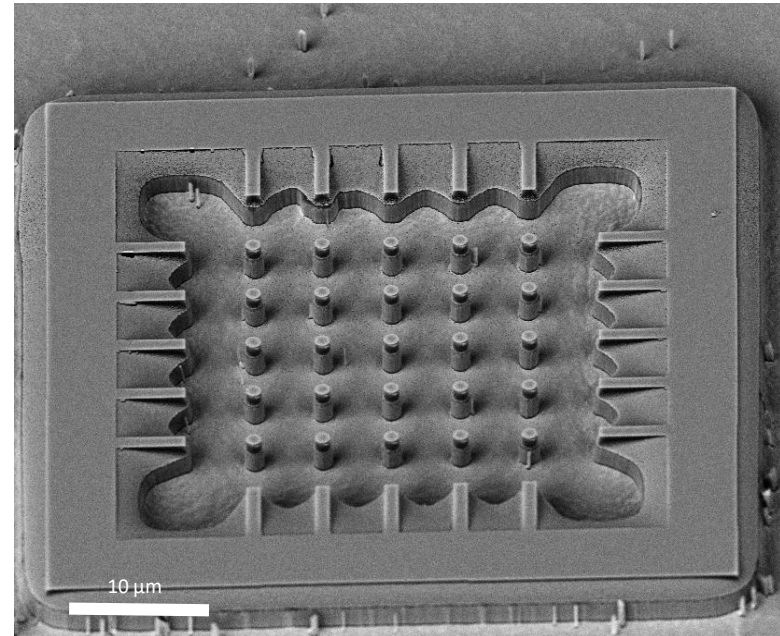


Understanding MACEtch

Separation between pillars = 5 μm



Array of \varnothing 300 nm pillars



Array of \varnothing 1100 nm pillars

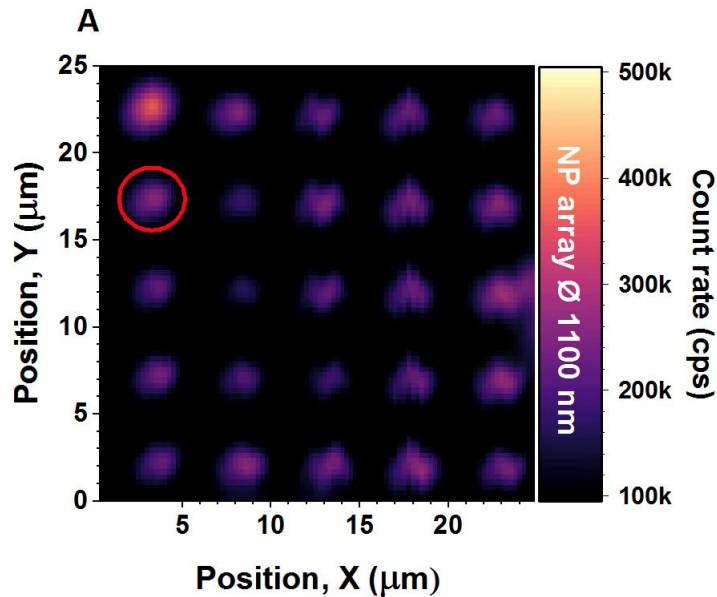
Slower etching for small structures far apart



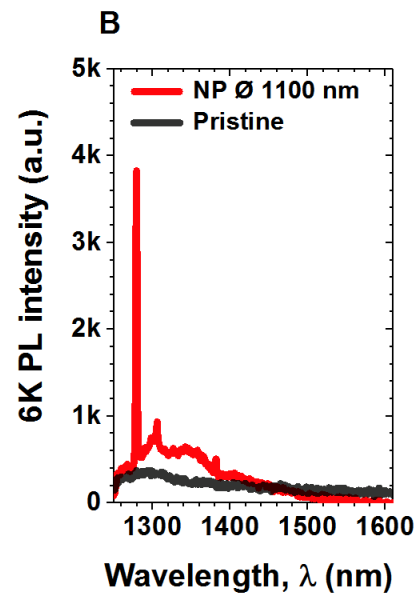
Ensembles of G-centers?

Carbon implantation post fabrication:

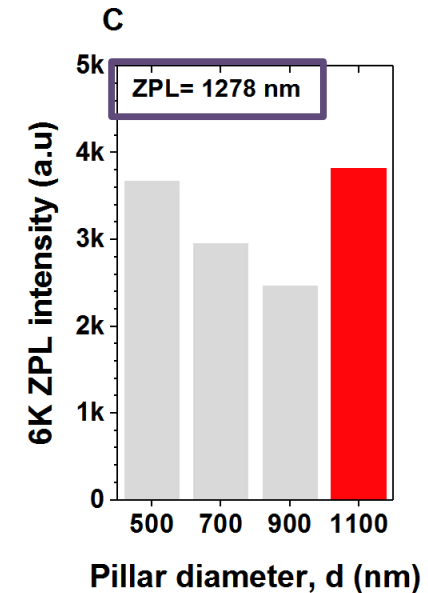
Fluence = $1 \times 10^{14} \text{ cm}^{-2}$, Energy = 250 keV, $R_p \sim 600 \text{ nm}$



2D PL scan of array
of \varnothing 1100 nm pillars



Optical fingerprint of G-centre: ZPL at 1278 nm



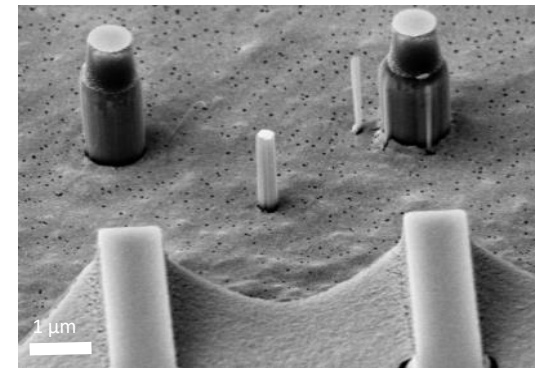
Successful fabrication of ensemble of G-centers in pillars

Manuscript in progress...



Conclusion and Outlook

- Fabrication of defect-free pillars by MACEtch
- Ensembles of G-centers in Si using broad beam carbon implantation
- Further MACEtch optimization
- Ensembles to Single G-centers in pillars
 - Implantation parameters
 - Focused Ion Beam



Towards Single Photon Emitters in Si...